

Search Notes

Application/Control No.

10/630,452

Examiner

Wenpeng Chen

Applicant(s)/Patent under
Reexamination

RITTER ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR, FPRS) - See search history printout.	10/4/06	me
IEEE Xplore - See search condition and result printout.	10/18/06	me